

Applicant: Luis Antonio Basto
For: UNIVERSALLY ACCESSIBLE FULLY PROGRAMMABLE MEMORY
BUILT-IN SELF-TEST (MBIST) SYSTEM AND METHOD

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ABSTRACT OF DISCLOSURE

A universally accessible fully programmable memory built-in self-test (MBIST) system including an MBIST controller having an address generator configured to generate addresses for a memory under test, a sequencer circuit configured to deliver test data to selected addresses of the memory under test and reading out that test data, a comparator
10 circuit configured to compare the test data read out of the memory under test to the test data delivered to the memory under test to identify a memory failure, and an externally accessible user programmable pattern register for providing a pattern of test data to the memory under test. The system includes an external pattern programming device configured to supply the pattern of test data to the user programmable data pattern
15 register.